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STN Database Summary Sheet

INPADOCDB (International Patent Documentation Database) contains the bibliographic and family data of patent documents and utility models of 80 patent-issuing organizations, including the European Patent Office (EPO) and World Intellectual Property Organization (WIPO). In addition, the legal status data of 49 patent-issuing organizations are included (36 countries plus the national phases PCT/EP from 13 countries). Patent citations from 13 countries are also available.

The database corresponds to the EPO Patent Information Resources (combined DOCDB-XML data and INPADOC Legal Status Service).

Subject Coverage

- All areas of science and technology, i.e., all classes of the International Patent Classification

Sources

- EPO-Patent Information Resource, based on the data supplied by the patent offices (INPADOC/DOCDB Service)
- INPADOC Legal Status Service

File Data

- 1836 to the present for patent records
- 1978 to the present for legal status events
- More than 55,000,000 records (applications) including national patent families with about 65 million published patent applications and 36 million families (3/09)
- More than 45 million legal status data in almost 16.2 million records (3/09)
- Updated weekly with about 70,000-1,000,000 records and 40,000-180,000 legal status data
- Automatic current-awareness searches (SDIs) are run weekly or monthly

User Aids

- Online Helps (HELP DIRECTORY lists all help messages available)
- STNGUIDESM
- http://www.stn-international.de/details_inpadocdb.html

Database Producer

European Patent Office Vienna sub-office
P.O. Box 90
A-1031 Vienna
Austria
Phone: (+43) 1/52126-0
Fax: (+43) 1/52126-5491
E-mail: inpadoc.help@epo.org

Database Supplier

FIZ Karlsruhe
P.O. Box 2465
D-76012 Karlsruhe
Germany
Phone: (+49) 7247/808-555
Fax: (+49) 7247/808-131
E-mail: helpdesk@fiz-karlsruhe.de

In North America

CAS
STN North America
P.O. Box 3012
Columbus, Ohio 43210-0012 U.S.A.

CAS Customer Care:
Phone: 800-753-4227 (North America)
614-447-3700 (worldwide)
Fax: 614-447-3751
E-mail: help@cas.org
Internet: www.cas.org

In Europe

FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49-7247-808-555
Fax: +49-7247-808-259
E-mail: helpdesk@fiz-karlsruhe.de
Internet: www.stn-international.de

In Japan

JAICI (Japan Association for
International Chemical Information)
STN Japan
Nakai Building
6-25-4 Honkomagome, Bunkyo-ku
Tokyo 113-0021, Japan
Phone: +81-3-5978-3601 (Technical Service)
+81-3-5978-3621 (Customer Service)
Fax: +81-3-5978-3600
E-mail: support@jaici.or.jp (Technical Service)
customer@jaici.or.jp (Customer Service)
Internet: www.jaici.or.jp

INPADOCDB

Search and Display Field Codes

The fields that allows left truncation and SLART (/BI, AB, TI) are indicated by an asterisk (*).

Bibliographic Search and Display Field Codes

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index * (contains single words from the title (TI) and the abstract (AB) fields)	None (or /BI)	S TUBULAR HEAT EXCHANG? S ALUM? (S) COAT? S ?MAGNET?	AB, ABDE, ABES, ABFR, ABOL, TI
Abstract * (contains AB, ABDE, ABES, ABFR, ABOL) (1,2)	/AB	S (DRILLING(W)PROCESS)/AB S ?COUPL?/AB	AB, ABDE, ABES, ABFR, ABOL
Abstract Language (ISO code and text)	/AL	S DUTCH/AL	ALL, ALLO, MAX, MAXO
Accession Number	/AN	S 12345678/AN	AN
Application Country	/AC	S WO/AC AND (INLAND (W) STEEL)/PA	AI
Application Date (3)	/AD	S 19840705/AD	AI
Application Kind Code	/AK	S WOW/AK	AI, AIT
Application Kind Code Text	/AIT	S ARA/AIT	AIT
Application Number (4)	/AP	S ZW1981-215/AP S 1981ZW-0000215/AP S DE1987-1603/AP S 1988/AY AND SIEMENS/PAS	AI
Application Year (3)	/AY	S ABFR A/CHG	CHG
Changes (indicator for changes in last update)	/CHG		
Citation Category	/CAT	S X/CAT	REN, REP
Data Availability	/DAV	S GAZETTE REFERENCE/DAV	DAV
Designated States	/DS	S W JP/DS	DS
Document Type (code and text)	/DT (or /TC)	S U/DT AND UNILEVER/PAS	DT
Entry Date (3,5)	/ED	S L1 AND ED>1 JAN 2007	ED
Entry Date and/or new Legal Status (3)	/EDLS	S EDLS=20070419	Not displayed
Entry Date New Patent Family (3)	/EDF	S 20070722/EDF	EDF
Entry Date Patent (3,5)	/EDP	S 20061130/EDP	EDP
Entry Date Priority (3,5)	/EDPR	S 20070401-20070429/EDPR	PRAI
Entry Week (INPADOC) (3,6)	/EW	S 199801/EW	EW
EPC, Keyword Terms	/EPC.KW	S D2/EPC.KW	EPC
European Patent Classification	/EPC	S A01B0015-20/EPC	EPC
Field Availability	/FA	S L7 AND DS/FA	FA
Filing Country for PCT Application	/AC.WO	S FR/AC.WO	AI
Filing Country for PCT Priorities (WIPO code and text)	/PRC.WO	S DE/PRC.WO	PRAI
Filing Details	/FDT	S DEC3D6/FDT	FDT
Indeling der Techniek (NL)	/IDT	S 12C2PE4/IDT	IDT
Indexing Codes (EPO)	/ICO	S K61M/ICO	ICO
Inventor	/IN (or /AU)	S NICKOLA RICHARD?/IN	IN
Inventor Address	/INA	S US/INA AND NICKOLA?/IN	INA
Inventor Address, Country	/IN.CNY	S US/IN.CNY	INA
Inventor INPADOC Standard	/INS	S AGARWAL S?/INS	INS
International Patent Classification (contains ICM, ICS, ICA, ICI, IPCI, IPCR)	/IPC	S H05B0006-36+NT/IPC S H05B0006-36-H05B0006-44/IPC	ICS, ICM, IPCI, IPCR

Bibliographic Search and Display Field Codes (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
IPC (contains ICM and ICS) Version 1-7 (7)	/IC	S C07H019-16/IC	IC
IPC, Action Date	/IPC.ACD	S 13 JAN 2006/IPC.ACD	IPC.TAB
IPC, Additional (supplementary) version 1-7 (7)	/ICA	S A61K037-64/ICA	ICA
IPC, Index (complementary), version 1-7 (7)	/ICI	S (C12P019-40(L)C12R001:465)/ICI	ICI
IPC, Keyword Terms	/IPC.KW	S INITIAL/IPC.KW	IPC.TAB
IPC, Main, version 1-7 (7)	/ICM	S C23C001-08)/ICM	ICM
IPC, Secondary (7)	/ICS	S C12P019-40/ICS	ICS
IPC, Version from IC	/IC.VER	S 7/IC.VER	IC.VER, IC
IPC, Version from IPC	/IPC.VER	S 200601/IPC.VER	IPC.TAB
Language (ISO code and text)	/LA	S DE/LA	LA
Language of Filing (ISO code and text)	/LAF	S FR/LAF	LAF
National Patent Classification	/NCL	S U1S1002/NCL	NCL
Non-Patent Literature XP- Document Number	/REXP	S XP002235691/REXP	REXP
Origin of Citation	/SRT	S SEA/SRT	REN, REP, REXP
Patent Assignee (8)	/PA (or /CS)	S INLAND STEEL/PA S BROWN WILLIAMSON/CS	PA
Patent Assignee Address	/PAA	S US/PAA AND ATOMIC ENERGY/PA	PAA
Patent Assignee Country	/PA.CNY	S GB/PA.CNY	PAS
Patent Assignee INPADOC Standard	/PAS	S INLAND STEEL CO?/PAS S (BROWN (S) TOBACCO)/PAS	PAS
Patent Country (WIPO code and text)	/PC	S DE/PC AND IBM/PAS AND 1988/PY	PI
Patent Information Publication Type	/PIT	S DEC0 GRANTED?/PIT	PIT
Patent Kind Code	/PK	S ZWA/PK	PI
Patent Number (4)	/PN (/PATS)	S FI990202U/PN	PI
Patent Status	/STA	S GRANTED/STA	STA
Priority Country (WIPO code and text)	/PRC	S JP/PRC AND 19880101/PRD	PRAI
Priority Date (3)	/PRD	S JP/PRC AND 19980101-19980331/PRD S 1980US-0167554/PRN	PRAI
Priority Kind Code	/PRK	S DEA1/PRK	PRAI
Priority Kind Text	/PRAIT	S	PRAIT
Priority Number (4)	/PRN	S US1990-169937/PRN	PRAI
Priority Year (3)	/PRY	S 1998/PRY AND US/PRC	PRAI
Priority Year, First (3)	/PRYF	S GB/PC AND 1998/PRYF	PRAI
Publication Date (3)	/PD	S 19990104/PD	PI
Publication Year (3)	/PY	S 1999/PY	PI
Referenced Non-Patent Literature	/REN	S MAYER/REN	REN
Referenced Patent Number	/RPN	S EP1234567/RPN	REP
Title * (1)	/TI	S (APPARAT? (S) SMOKE (S) FILTER##)/TI	TI
Title Language (ISO code and text)	/TL	S EN/TL S ENGLISH/TL	TL

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Bibliographic Search and Display Field Codes (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Update Date (3)	/UP	S L1 AND UP>20070102	UP
Update Date of BIB fields	/UPBB	S L1 AND UPBB>20070222	UPALL
Update Date of Classifications (3)	/UPCC	S L1 AND UPCC>20070222	UPALL
Update Date Legal Status (3)	/UPLS	S UPLS=20070329	LS, LSUP
Update Date All Patent Changes (3)	/UPM	S L1 AND 20070329/UPM	Not displayed
Update Date New Patent Family Record (3)	/UPFD	S 20070215/UPFD	UPALL
Update Date New Publication and/or Legal Status changes (3)	/UPFE	S 20070321/UPFE	UPALL
Update Date Patent Family (All Updates) (3)	/UPFA	S 20070329/UPFA	UPALL
Update Date Patent Family Bibliographic (3)	/UPFB	S 20070215/UPFB	UPALL
Update Date Patent Family Legal Status (3)	/UPFL	S 20070321/UPFL	UPALL
Update Date Patent Family Publication Level (3)	/UPFP	S 20070222/UPFP	UPALL
Update Week (INPADOC week) (3)	/UW	S UW=200601	UW

- (1) In addition to right truncation, left and simultaneous left and right truncation are available in this field. At least 4 characters need to be used for the length of the stem.
- (2) This field is available for selected countries and patent publications. See HELP CONTENT.
- (3) Numeric search field that may be searched by using numeric operators or ranges.
- (4) Either STN or Derwent format may be used.
- (5) Available since 2006.
- (6) Available since week 200639.
- (7) Search in IPC8 format also available.
- (8) Search with implied (S) proximity is available in this field.

Super Search Fields (1)

Search Field Name	Search Code	Search Examples	Display Codes
Application Number Group (1)	/APPS (/AP, /PRN)	S DE1984-3400052/APPS S 1984DE-3400052/APPS	AI, PRAI
Inventor Group	/INSS (/IN, /INS, /LSIN)	S MEIER/INSS	IN, INS, LS
Patent Assignee Group	/PASS (/PA, /PAS, /LSPA)	S MEIER/PASS	PA, PAS, LS
Patent Countries	/PCS (/DS, /PC)	S DE/PCS	DS, PI

- (1) Enter a supersearch code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual filed codes instead.
- (2) Either STN or Derwent format may be used.

Legal Status Search and Display Field Codes

Search Field Name	Search Code	Search Examples	Display Codes
Entry Date new publication and/or new Legal Status (1)	/EDLS	S EDLS=FEB 2007	Not displayed
Entry Week Legal Status (1)	/EWLS	S 200641-200642/EWLS	LS
Legal Status Basic Index (contains legal status agent (LSAG), legal status free format text (LSFT), legal status inventor (LSIN), legal status patent opponent (LSOP) and legal status patent assignee (LSPA) fields)	/LSBI	S LASER?/LSBI S ANACOMP/LSBI S OPPOSITE/LSBI	LS
Legal Status Code (code and text)	/LSC	S EP111L/LSC	LS
Legal Status Code Category	/LSC2	S NIF/LSC2	LS
Legal Status Code Country (WIPO code and text)	/LSCC	S BE/LSCC	LS
Legal Status Code Text	/LSTX	S CORRECTION/LSTX	LS
Legal Status Country (WIPO code and text)	/LSCY	S UNITED KINGDOM/LSCY	LS
Legal Status Date in Force (1)	/LSDF	S LSDF=20050109	LS
Legal Status Date INPADOC Gazette (1)	/LSD	S LSD=Jan 2002	LS
Legal Status Designated States (WIPO code and text)	/LSDS	S AU/LSDS S AUSTRALIA/LSDS	LS
Legal Status Extension State, Payment Country	/LSXS.CY	S MK/LSXS.CY	LS
Legal Status Extension State, Payment Date (1)	/LSXS.DT	S 20030611/LSXS.DT	LS
Legal Status Free Format Text	/LSFT	S TELECOMMUNICATION/LSFT	LS
Legal Status Indicator	/LSCI	S POSTIVE/LSCI	LS
Legal Status IPC	/LSIC	S 41J320/0/LSIC	LS
Legal Status List of Countries (ISO code and text)	/LSLCY	S ROMANIA/LSLCY	LS
Legal Status Patent Assignee	/LSPA	S MAN(S)CERAMICS)/LSPA	LS
Legal Status Patent Inventor	/LSIN	S MAYER, BERND/LSIN S (MAYER(S)BERND/LSIN	LS
Legal Status Patent Opponent	/LSOP	S SIEMANS AG/LSOP	LS
Legal Status Payment Year	/LSPMY	S 18/LSPMY	LS
Legal Status Publication Country (WIPO code and text)	/LSPC	S CA/LSPC S CANADA/LSPC	LS
Legal Status Publication Date (1)	/LSPD	S LSPD=JAN 1998	LS
Legal Status Publication Kind Code	/LSPK	S ES00/LSPK	LS
Legal Status Publication Number	/LSPN	S EP200212/LSPN	LS
Legal Status Publication Year (1)	/LSPY	S 1999-2000/LSPY	LS
Legal Status Representative/Agent	/LSAG	S (LORENZ AND PHILIPPS)/LSAG	LS
Legal Status SPC Number	/LSSPC	S EU/1/00/137/011/LSSPC	LS
Legal Status SPC, Expiry Date (1)	/LSSPC.XD	S LSSPC.XD>2005	LS
Legal Status SPC, Extension Date (1)	/LSSPC.EX	S 20100901/LSSPC.EX	LS
Legal Status SPC, Filing Date (1)	/LSSPC.FD	S 19950101-19961231/LSSPC.FD	LS
Update Date Legal Status	/UPLS	S 20040806/UPLS	LS

(1) Numeric search field that may be searched by using numeric operators or ranges.

INPADOCDB

DISPLAY and PRINT Formats

Any combination of display fields and formats may be used to display or print answers. Multiple codes must be separated by commas or spaces, e.g., D L1 1-5 TI IN. The fields are displayed or printed in the order requested.

You can combine all display fields and all display formats with the qualifier .M to display the content for all publications of a record.

Hit-term highlighting is available for most display fields. Highlighting must be ON during SEARCH in order to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB	Abstract	D AB
ABDE	Abstract in German	D ABDE
ABEQ	Abstract in English equivalent	D ALL
ABES	Abstract in Spanish	D ABES
ABFR	Abstract in French	D ABFR
ABOL	Abstract in Other Language	D ABOL
AI (1)	Application Information	D AI PI
AIT	Application Kind Code Text	D AIT
AN	Accession Number	D AN
APPS	Application Number Group	D APPS
CHG	Changes (indicator for changes in the last update)	D CHG
DAV	Data Availability	D DAV
DS	Designated State	D DS
DT (TC)	Document Type	D DT
ED	Entry Date	D 1-5 ED UP
EDP	Entry Date Patent	D 1-5 EDP
EPC	European Patent Classifications (EPC, ICO, IDT)	D EPC
EW	Entry Week	D EW
FA	Field Availability	D TI FA
FDT (PT)	Filing Details	D PN FDT
FN	Family Number	D FN
IC	International Patent Classification (ICM, ICS)	D IC
ICA	IPC, Additional (supplementary)	D ICA
ICI	IPC, Index (complementary)	D ICI
ICM	IPC, Main	D ICM L7
ICS	IPC, Secondary	D ICS
IN	Inventor	D IN PA
IN.M	Inventor for all levels	D IN.M
INA (IN.CNY)	Inventor Address	D IN INA
INS (AU)	Inventor INPADOC Standard	D INS
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	D LA
LAF	Language of filing	D LAF
NCL	National Patent Classification	D NCL
PA (CS)	Patent Assignee	D PA TI 1-10
PAA	Patent Assignee Address	D PA PAA
PAS	Patent Assignee INPADOC Standard	D PAS
PI (PN,PATS) (1)	Patent Information	D PI PRAI
PIT	Patent Information Publication Type	D PIT 1-5
PRAI (PRN) (1)	Priority Information	D PRAI
PRAIT (1)	Priority Kind Code Text	D PRAIT
REC (RE.CNT)	Reference Count	D REC
REN (NPL)	Reference Non-Patent Literature	D REN
REP	Referenced Patents	D REF
REXP	Non-Patent Literature XP-Document Number	D REXP
STA	Patent Status	D STA

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
TI TL UP UW	Title Title Language Update Date Update Week	D TI D TL D UP LS D UW
ABS (4) ALL (1,4) ALLO APPS (2) BIB (1) IALL (1) IBIB (1) IBIB.M (2) IC (1) IMAX IND IPC IPC.TAB LS LSUP MAX (1,4) MAXO (4) MAXO2 RE SCAN (2) STD TRIAL (TRI, FREE, SAMPLE, SAM) (1)	AN, AB, ABDE, ABES, ABFR, ABOL, ABEQ BIB, all abstracts, IND, FA, CHG ALL for previous update AI, PRAI AN, FN, ED, UP, TI, IN, INS, INA, PA, PAS, PAA, LA, LAF, TL, DT, PIT, PI, DS, AI, PRAI, REC ALL, indented with text labels BIB, indented with text labels BIB.M, indented with text labels ICM, ICS MAX, identified with text labels AN, ED, EW, UP, UW, ICO, IPC,EPC, IDT, NCL ICM, ICS, ICA, ICI, IPCI, IPCR IPC, IPC.KW, IPC.ACD, IPC.VER AN, UPLS, Legal Status Last LS Update AN, ED, EW, UP, UW, TI, IN, INS, INA, PA, PAS, PAA TL, LA, DT, PIT, FDT, PI, DS, AI, PRAI, AIT, PRAIT, OSCA, OSDW, ICM, ICS, ICA, ICI, NCL, EPC (for all levels), AB, LS Max, with original data in UTF-8 Characters MAXO, plus display of special characters in the abstract Cited References (REP, REXP, REN) TI latest publication (random display without answer number) BIB, IND TI, FA	D ABS D ALL L6 D ALLO D APPS D 8 BIB D IALL L3 7 D 5 IBIB D 5 IBIB.M D 1,3,5 IC D IMAX D L5 IND D IPC D IPC.TAB D LS D LSUP D MAX 1 3 D MAXO D MAXO2 D RE D SCAN D STD D TRIAL TOTAL
BIBLS (1) CFAM (1) CFAM.PD CFAM2 (1) DFAM (1) DFAM.AD DFAM.AP DFAM.PD DFAM.PN DFAM.PRD EFAM (1) EFAM. PRD FAM (1) FAMLS (1) FAM.PRD FAM2 (1) FFAM (1) FFAM.PC (1,3) FFAMED (1) FFAMED4 (1) FFAMED.PC (1,3) FFAMUP (1) FFAMUP.PC (1,3) FFAMUP4 (1) IFAM IFAMED (1) IFAMED4 (1)	BIB + LS for all patent family members Condensed FAM with only PI in the table CFAM, sorted by Publication Date Condensed FAM (PI, AI, PRAI) FAM, delimited for post processing DFAM, sorted by Application Date DFAM, sorted by Application Number DFAM, sorted by Patent Date DFAM, sorted by Patent Number DFAM, sorted by Priority Date FAM, but the priority information constitutes the header EFAM, sorted by Priority date AN, table of patent family information CFAM2 plus a list of all legal status entries, sorted by legal status date (LSD) FAM sorted by Priority Date AN, table of patent family information, another order STD + LS for each member of the family STD + LS for the equivalent in the specified country STD for new publications and/or LSUP for each updated family STD for new publications and/or LSUP for each updated family (monthly) STD for new publications and/or LSUP for each updated family STD + LS for each updated family (current update only) STD + LS for each updated family (current update only) STD + LS for each updated family (monthly update only) Combines indented FAM and IMAX.F Indented FFAMED plus patent family table Indented FFAMED4 plus patent family table	D BIBLS D CFAM D CFAM.PD D CFAM2 D DFAM D DFAM.AD D DFAM.AP D DFAM.PD D DFAM.PN D DFAM.PRD D EFAM D EFAM.PRD D FAM D FAMLS D FAM.PRD D FAM2 D FFAM D FFAM.WO D FFAMED D FFAMED4 D FFAMED.EP D FFAMUP D FFAMUP.EP D FFAMUP4 D IFAM D IFAMED D IFAMED4

INPADOCDB**DISPLAY and PRINT Formats (cont'd)**

Format	Content	Examples
IFAMUP IFAMUP4 LFAM LFAMUP LFAMUP.PC (3) LFAMUP4 (1) MFAM (1) PILS.F SFAM (1) TIPI.F UPALL	Indented FFAMUP plus patent family table Indented FFAMUP4 plus patent family table AN, PI, LSUP for all members of a patent family AN, PI, LSUP for all updated members of a patent family (current update only) AN, PI, LSUP for all updated members of a patent family AN, PI, LSUP for all updated members of a patent family (monthly) MAX for each family member PI + LS for all patent family members FAM sorted by EPO "simple patent family" TI + LS for all patent family members Table of update dates UPBB, UPCC, EDP, EDF, UPFD, UPFP, UPFB, UPFL	D IFAMUP D IFAMUP4 D LFAM D LFAMUP D LFAMUP.US D LFAMUP4 D MFAM D PILS.F D SFAM D TIPI.F D UPALL
HIT KWIC OCC (1)	Fields containing hit terms Hit terms with 50 words on either side (KeyWord-In-Context) Number of occurrences of hit terms and fields in which they occur	D HIT NOH D KWIC D OCC

- (1) By default, patent, application, and priority numbers are displayed in STN format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN format, enter SET PATENT STN.
- (2) SCAN must be entered on the command line, i.e., D SCAN or DISPLAY SCAN.
- (3) PC = AT, BE, CA, CH, CN, DE, DK, EP, ES, FI, FR, GB, JP, KR, NL, NO, RU, SE, US, WO.
- (4) ABEQ only for records entered or updated after week 200740.

IPC Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-7, use the field code followed by the edition number, e.g., /IPC2, for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

Relationship Code	Content	Example
ADVANCED (ADV)	Advanced Level Codes for the Core Level IPC Code	E A61K0066-02+ADVANCED/IPCI
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (SELF, BT)	E C01F001-00+BT/IPC
BTn	Broader Term (SELF, BT) up to the next n levels (n=1,2,3...)	E C01F001-21+BT2/IPC
Core (COR)	Core Codes for the Advanced Level IPC Codes	E G08C0019-22=COR/IPC
ED	Complete title of the SELF term and IPC manual	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E C011003-00+HIE/IPC
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
NTn	Narrower Terms (SELF, NT) down to the next n levels (n=1,2...)	E C01C+NT3/IPC
PREVn	Previous Classification (n =1,2,...)	E C01C001-12+PREV10/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C003-20+RT/IPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01F001-00+TI/IPC

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y	A
Abstract in French	ABFR	Y (7)	A
Abstract in German	ABDE	Y (7)	A
Abstract in Other Language	ABOL	Y (7)	A
Abstract in Spanish	ABES	Y (7)	A
Application Country	AC	Y	A
Application Date	AD	Y	N
Application Information	AI	Y (2)	A
Application Kind Code	AK	Y	A
Application Kind Code Text	AIT	Y	A
Application Number	AP	Y	A
Application Number Group	APPS	Y (2,3)	-
Application Year	AY	Y	N
Designated State	DS	Y	-
Document Type	DT (TC)	Y	-
Entry Date	ED	Y	-
Entry Date Patent	EDP	Y	-
European Patent Classification	EPC	Y	Y
Entry Week	EW	Y	N
Indeling der Techniek (NL)	IDT	Y	A
Indexing Codes (EPO)	ICO	Y	A
International Patent Classification	IC	Y	-
International Patent Classification	IPC	Y	-
Inventor	IN	Y	A
Inventor Address	INA	Y	A
Inventor Country	IN.CNY	Y	A
Inventor INPADOC Standard	INS (AU)	Y	A
IPC, Additional (supplementary)	ICA	Y	A
IPC Advanced Level Symbols	IPC.A	Y	-
IPC Advanced Level Symbols for Invention	IPC.AI	Y (4)	-
IPC Core Level Symbols	IPC.C	Y (4)	-
IPC Core Level Symbols for Invention	IPC.CI	Y (4)	-
IPC, Index (complementary)	ICI	Y	A
IPC, Initial	IPCI (4)	Y	-
IPC, Main	ICM	Y	A
IPC, Reclassified	IPCR (4)	Y	-
IPC, Secondary	ICS	Y	A
Language	LA	Y	A
Language of Filing	LAF	Y	A
Legal Status Code	LSC	Y	-
Legal Status Code Category	LSC2	Y	A
Legal Status Code Country	LSCC	Y	-
Legal Status Date INPADOC GAZETTE	LSD	Y	-
Legal Status Free Format Text	LSFT	Y	-
Legal Status IPC	LSIC	Y	-
Legal Status Patent Assignee	LSPA	Y	-
Legal Status Patent Inventor	LSIN	Y	-
Legal Status Patent Opponent	LSOP	Y	-
Legal Status Payment Year	LSPMY	Y	-
Legal Status Publication Country	LSPC	Y	-
Legal Status Publication Date	LSPD	Y	-

INPADOCDB**SELECT, ANALYZE, and SORT Fields (cont'd)**

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Legal Status Publication Number	LSPN	Y	-
Legal Status Representative/Agent	LSAG	Y	-
Legal Status SPC Number	LSSPC	Y	-
Legal Status SPC, Expiry Date	LSSPC.XD	Y	-
Legal Status SPC, Extension Date	LSSPC.EX	Y	-
Legal Status SPC, Filing Date	LSSPC.FD	Y	-
National Patent Classification	NCL	Y	A
Non-Patent Literature XP-Document Number	REXP	Y	A
Occurrence Count of Hit Terms	OCC	N	N
Patent Assignee	PA (CS)	Y	A
Patent Assignee Address	PAA	Y	A
Patent Assignee, Country	PA.CNY	Y	A
Patent Assignee, Max.	PA.M	Y	-
Patent Assignee INPADOC Standard	PAS	Y	A
Patent Country	PC	Y	A
Patent Countries	PCS	Y (5)	-
Patent Information	PI	Y (6)	Y
Patent Information Publication Type	PIT	Y	A
Patent Kind Code	PK	Y	A
Patent Number	PN (PI, PATS)	Y (2)	A
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006 to the present	IPC.F (4)	Y	-
Priority Country	PRC	Y	A
Priority Date	PRD	Y	N
Priority Kind Code	PRK	Y	A
Priority Kind Text	PRAIT	Y	A
Priority Number	PRN (PRAI)	Y (2)	A
Priority Year	PRY	Y	N
Priority Year, First	PRYF	Y (6)	N
Publication Date	PD	Y	N
Publication Year	PY	Y	N
Referenced Non-Patent Literature	REN	Y	A
Referenced Patents	REP	Y	A
Related Patent Information	RLI	Y	-
Title	TI	Y	A
Title Language	TL	Y	A
Update Date	UP	Y	N
Update Date Legal Status	UPLS	-	-
Update Week	UW	Y	-

(1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.

(2) SELECTed and SORTed application, priority, and patent numbers are in the format set by the SET PATENT command, either DERWENT or STN.

(5) Selects patent country and designated states and appends /PCS.

(6) SELECT or ANALYZE HIT are not valid with this field.

(7) Appends /AB to the terms created by SELECT.

Sorting within the Patent Family Display Formats

In family displays, answers are sorted by a specific field by default. You can define the sort parameter in family display formats by appending the desired field to the format, e.g., DFAM.AD, to have the answers sorted by the Application Date rather than the default priority number.

Format	Sorted by
CFAM	AP (Application Number)
CFAM.PD	Publication Date
DFAM	PRN (Priority Number)
DFAM.AD	Application Date
DFAM.AP	Application Number
DFAM.PD	Patent/Publication Date
DFAM.PN	Patent Number
DFAM.PRD	Priority Date
EFAM	PRN (Priority Number)
EFAM.PRD	Priority Date
FAM	PRN (Priority Number)
FAM.PRD	Priority Date
FFAM	PN (Patent Number) of the highest level
LFAM	PN (Patent Number) of the highest level

Update Codes (for SDI also)

Update codes or entry dates associated with records

Search Field Name	Search Code	Search Examples	Display Codes
All updates of a record	/UPM	S 20070215/UPM	Not displayed
Entry Date	/ED	S L1 AND ED>1 DEC 2006	ED
Entry Date Patent	/EDP	S 20061026/EDP	EDP, UPALL
Entry Date Priority	/EDPR	S 20030707-20030714/EDPR	EDP, PRAI
Update Date	/UP	S 20070102/UP	LS
Update Date Legal Status	/UPLS	S 20070222/UPLS	LS

Update codes or entry dates associated with patent families **(1,2)**

Search Field Name	Search Code	Search Examples	Display Codes
All changes in a patent family	/UPFA	S L1 AND 20070329/UPFA	Not displayed
Any change of a Bibliographic Element in a patent family	/UPFB	S L1 AND 20070215/UPFB	UPALL
Any change of Legal Status in a patent family	/UPFL	S L1 AND 20070321/UPFL	UPALL
Entry Date new patent family	/EDF	S L1 AND EDF>21 MAR 2007	UPALL
Entry Date new publication and changes in legal status	/EPFE	S L1 AND 20070321/UPFE	Not displayed
Entry Date new record (document) into a patent family (level 1)	/UPFD	S L1 AND 20070215/UPFD	UPALL
Entry Date new publication level into a patent family	/UPFP	S L1 AND 20070222/UPFP	UPALL

(1) Available since February 2007.

(2) Special display format available for monitoring patent families.

INPADOCDB

Sample Records

DISPLAY MAX

AN 24180089 INPADOCDB UP 20061123

TI Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.
Coated sheet cutting method and apparatus.
Procede et appareil pour la coupe d'une feuille revetue.

TL German; English; French

IN KAWAI, HIROKAZU

INS KAWAI HIROKAZU, JP

PA FUJI PHOTO FILM CO., LTD.

PAS FUJI PHOTO FILM CO LTD, JP

DT Patent

PI EP 1488896 A1 20041222 English

PIT EPA1 APPLICATION PUBLISHED WITH SEARCH REPORT

DAV 20041222 examined-printed-without-grant

STA PRE-GRANT PUBLICATION

DS R: DE FR GB

AI EP 2004-13971 A 20040615

AIT EPA Patent application

PRAI JP 2003-174783 A 20030619 (JPA)
JP 2003-174784 A 20030619 (JPA)

PRAIT JPA Patent application

REP JP 2001138285 (SEA, npl, Cat: Y)
JP 6168444 (SEA, npl, Cat: Y)

REXP XP000510813 (SEA, Cat: A)

REN (1) PATENT ABSTRACTS OF JAPAN vol. 2000, no. 22, 9 March 2001
(2001-03-09) & JP 2001 138285 A (SONY CORP), 22 May 2001 (2001-05-22)
(2) PATENT ABSTRACTS OF JAPAN vol. 0185, no. 05 (P-1803), 21 September
1994 (1994-09-21) & JP 6 168444 A (MATSUSHITA ELECTRIC IND CO LTD), 14
June 1994 (1994-06-14)
(3) KLEIN H: "LANGSSCHNEIDEN VON BAHNFORMIGEN MATERIALIEN DER
KREISMESSER-SCHERENSCHNITT UND SEINE OPTIMALE EINSTELLUNG FUR DAS
LANGSSCHNEIDEN BAHNFORMIGER MATERIALIEN (TEIL 3)" COATING, VERLAG COATING
THOMAS & CO, CH, vol. 28, no. 5, 1 May 1995 (1995-05-01), pages 176-179,
XP000510813 ISSN: 0590-8450

IC.V 7

ICM B26D0001-24

IPCR B26D0001-24 [I,A]; B26D0007-26 [N,A]
B26D0001-01 [I,C*]; B26D0007-26 [N,C*]

EPC B26D0001-24B

ICO L26D0007:26C2

AB A discoid lower blade and a discoid upper blade, having a sharper knife angle compared with that of the lower blade, are arranged such that rotational axes thereof are parallel to each other, and portions of the blades overlap one another in the direction that the rotational axes extend. A sheet with a coating layer on one side is fed through and shear-cut between the upper and lower blades in the direction perpendicular to the rotational axes, with the surface of the sheet opposite the coating layer in contact with a periphery of the lower blade while the blades are rotated. When the sheet is shear-cut, a contact start position, where contact between the sheet and the upper blade starts, is positioned upstream in the feed direction of the sheet but outside a contacting area of the sheet, where the sheet contacts the periphery of the lower cutting blade. Alternatively, the contact start position starts within the contacting area and an overlap between a part of the upper cutting blade and a part of the lower cutting blade is maintained less than 1.5 mm. <IMAGE>.

AL English

AS EPO

FA AB; AI; AN; DAV; DS; DT; EPC; ICM; ICO; IN; INS; IPC; IPCR; LA; PA; PAS;
PI; PIT; PRAI; REN; REP; REXP; TI

AN 24180089 INPADOCDB UP 20061005
 TI Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.
 Coated sheet cutting method and apparatus.
 Procède et appareil pour la coupe d'une feuille revetue.
 TL German; English; French
 IN KAWAI, HIROKAZU
 INS KAWAI HIROKAZU, JP
 PA FUJI PHOTO FILM CO., LTD.
 PAS FUJI PHOTO FILM CO LTD, JP
 DT Patent
 PI EP 1488896 B1 20061004 English
 PIT EPB1 PATENT SPECIFICATION
 DAV 20061004 printed-with-grant
 STA GRANTED
 DS R: DE FR GB
 AI EP 2004-13971 A 20040615
 AIT EPA Patent application
 PRAI JP 2003-174783 A 20030619 (JPA)
 JP 2003-174784 A 20030619 (JPA)
 PRAIT JPA Patent application
 IPCI B26D0001-24 [I,A]; B26D0001-01 [I,C*]
 IPCR B26D0007-26 [N,A]
 B26D0007-26 [N,C*]
 EPC B26D0001-24B
 ICO L26D0007:26C2
 FA AI; AN; DAV; DS; DT; EPC; ICO; IN; INS; IPC; IPCI; IPCR; LA; PA; PAS; PI;
 PIT; PRAI; TI

LEGAL STATUS

AN 24180089 INPADOCDB
 20041222 EPAK + DESIGNATED CONTRACTING STATES:
 EP A1
 AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IT LI LU
 MC NL PL PT RO SE SI SK TR
 20041222 EPAX + EXTENSION OF THE EUROPEAN PATENT TO
 AL HR LT LV MK
 20050803 EP17P + REQUEST FOR EXAMINATION FILED
 20050603
 EXA Examination, Search Report
 20050914 EPAKX + PAYMENT OF DESIGNATION FEES
 DE FR GB
 20061004 EPAK + DESIGNATED CONTRACTING STATES:
 EP B1
 DE FR GB
 20061004 EPREG REFERENCE TO A NATIONAL CODE
 GBFG4D + GB: EUROPEAN PATENT GRANTED
 200641
 20061116 EPREF CORRESPONDS TO:
 DE 602004002620 P 20061116
 200646

INPADOCDB**DISPLAY FAM**

PATENT FAMILY INFORMATION
AN 24180089 INPADOCDB

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JP 2003-174783      A  20030619      CN 2004-10059710      A  20040617
                                         DE 2004-602004002620 T  20040615
                                         EP 2004-13971          A  20040615
JP 2003-174784      A  20030619      JP 2003-174783      A  20030619
                                         US 2004-868808        A  20040617
                                         CN 2004-10059710      A  20040617
                                         DE 2004-602004002620 T  20040615
                                         EP 2004-13971          A  20040615
                                         JP 2003-174784        A  20030619
                                         US 2004-868808        A  20040617

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CN 2004-10059710      A  20040617      CN 1572446           A  20050202
DE 2004-602004002620 T  20040615      DE 602004002620      D1 20061116
EP 2004-13971          A  20040615      EP 1488896           A1 20041222
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US 2004-868808        A  20040617      US 20040255743      A1 20041223

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2 priorities, 6 applications, 7 publications

DISPLAY DFAM

PATENT FAMILY INFORMATION
AN 24180089 INPADOCDB

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JP 2003-174783      A  20030619;CN 2004-10059710      A  20040617;CN 1572446
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  602004002620      D1 20061116;|
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  A1 20041222;|
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  B1 20061004;|
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  A  20050113;|
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  20040255743      A1 20041223;|
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  A  20050202;|
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  A1 20041222;|
JP 2003-174784      A  20030619;EP 2004-13971          A  20040615;EP 1488896
  B1 20061004;|
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  A  20050113;|
JP 2003-174784      A  20030619;US 2004-868808        A  20040617;US
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